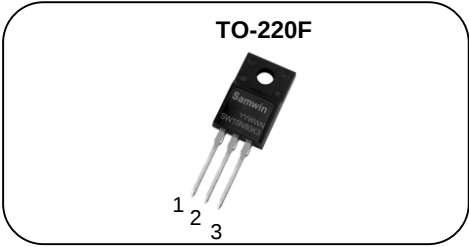


N-channel Enhanced mode TO-220F MOSFET

Features

- High ruggedness
- Low $R_{DS(ON)}$ (Typ 0.21Ω)@ $V_{GS}=10V$
- Low Gate Charge (Typ 47nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: Charger, LED, PC Power



1. Gate 2. Drain 3. Source

BV_{DSS} : 800V
I_D : 15A
R_{DS(ON)} : 0.21Ω



General Description

This power MOSFET is produced with advanced super junction technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW F 15N80K3	SW15N80K3	TO-220F	TUBE

Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DSS}	Drain to source voltage	800	V
I _D	Continuous drain current (@T _C =25°C)	15*	A
	Continuous drain current (@T _C =100°C)	9.5*	A
I _{DM}	Drain current pulsed (note 1)	45	A
V _{GS}	Gate to source voltage	±30	V
E _{AS}	Single pulsed avalanche energy (note 2)	180	mJ
E _{AR}	Repetitive avalanche energy (note 1)	18	mJ
dv/dt	MOSFET dv/dt ruggedness (@V _{DS} =0~400V)	30	V/ns
dv/dt	Peak diode recovery dv/dt (note 3)	20	V/ns
P _D	Total power dissipation (@T _C =25°C)	54.3	W
	Derating factor above 25°C	0.43	W/°C
T _{STG} , T _J	Operating junction temperature & storage temperature	-55 ~ + 150	°C
T _L	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds.	300	°C

*. Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Value	Unit
R _{thjc}	Thermal resistance, Junction to case	2.3	°C/W
R _{thja}	Thermal resistance, Junction to ambient	43	°C/W

Electrical characteristic (T_j = 25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
Off characteristics						
BV _{DSS}	Drain to source breakdown voltage	V _{GS} =0V, I _D =250μA	800			V
ΔBV _{DSS} / ΔT _j	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C		0.6		V/°C
I _{DSS}	Drain to source leakage current	V _{DS} =800V, V _{GS} =0V			1	μA
		V _{DS} =640V, T _j =125°C			50	μA
I _{GSS}	Gate to source leakage current, forward	V _{GS} =30V, V _{DS} =0V			100	nA
	Gate to source leakage current, reverse	V _{GS} =-30V, V _{DS} =0V			-100	nA
On characteristics						
V _{GS(TH)}	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250μA	2.5		4.5	V
R _{DS(ON)}	Drain to source on state resistance	V _{GS} =10V, I _D =7.5A, T _j =25°C		0.21	0.24	Ω
		V _{GS} =10V, I _D =7.5A, T _j =125°C		0.46		Ω
G _{fs}	Forward transconductance	V _{DS} =30V, I _D =7.5A		23		S
Dynamic characteristics						
C _{iss}	Input capacitance	V _{GS} =0V, V _{DS} =200V, f=1MHz		2378		pF
C _{oss}	Output capacitance			58		
C _{rss}	Reverse transfer capacitance			1.6		
t _{d(on)}	Turn on delay time	V _{DS} =400V, I _D =15A, R _G =10Ω, V _{GS} =10V (note 4,5)		35		ns
t _r	Rising time			40		
t _{d(off)}	Turn off delay time			72		
t _f	Fall time			38		
Q _g	Total gate charge	V _{DS} =640V, V _{GS} =10V, I _D =15A I _G =4mA (note 4,5)		47		nC
Q _{gs}	Gate-source charge			13		
Q _{gd}	Gate-drain charge			17		
R _g	Gate resistance	f=1MHz		8		Ω

Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I _S	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			15	A
I _{SM}	Pulsed source current				45	A
V _{SD}	Diode forward voltage drop.	I _S =15A, V _{GS} =0V			1.4	V
t _{rr}	Reverse recovery time	I _S =15A, V _{GS} =0V, di _f /dt=100A/μs		377		ns
Q _{rr}	Reverse recovery charge			6		uC

※. Notes

1. Repeitative rating : pulse width limited by junction temperature.
2. L =40mH, I_{AS} =3A, V_{DD}=100V, R_G=25Ω, Starting T_j = 25°C
3. I_{SD} ≤ 15A, di/dt = 100A/μs, V_{DD} ≤ BV_{DSS}, Staring T_j =25°C
4. Pulse Test : Pulse Width ≤ 300μs, duty cycle ≤ 2%.
5. Essentially independent of operating temperature.

Fig. 1. On-state characteristics

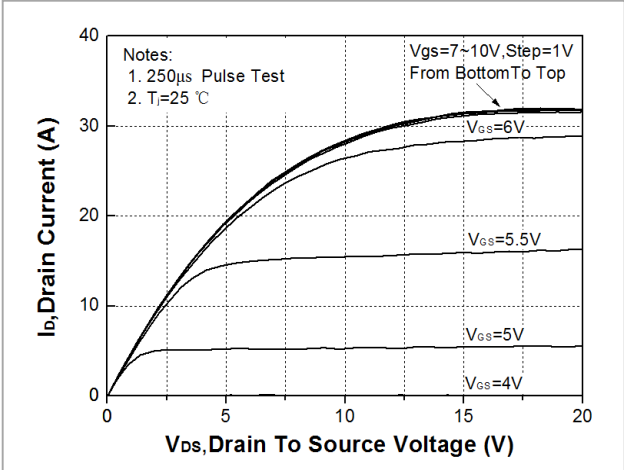


Fig. 2. Transfer Characteristics

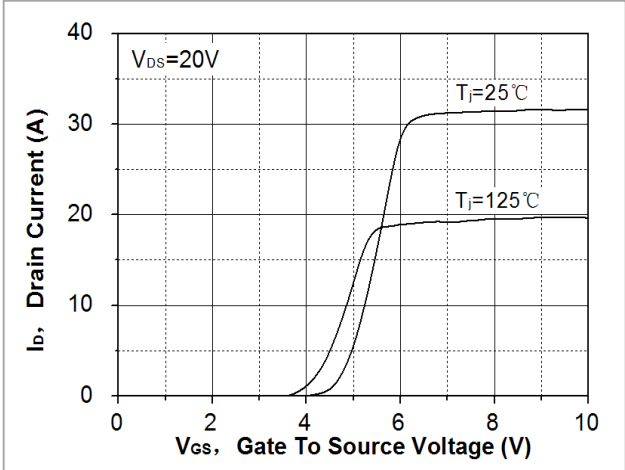


Fig. 3. On-resistance variation vs. drain current and gate voltage

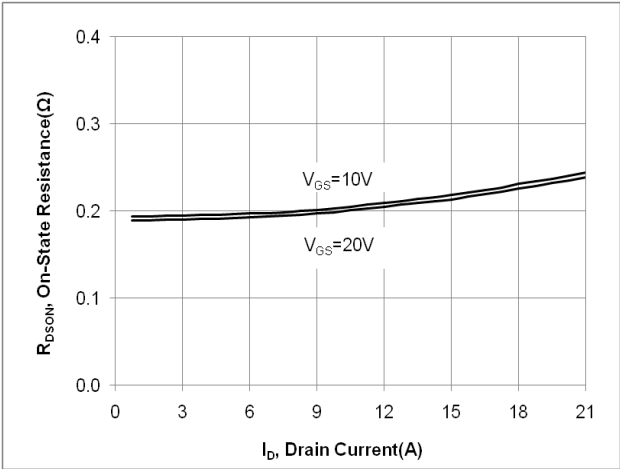


Fig. 4. On-state current vs. diode forward voltage

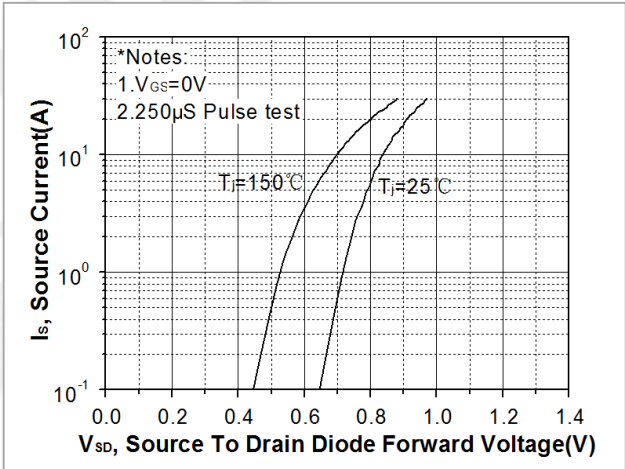


Fig 5. Breakdown voltage variation vs. junction temperature

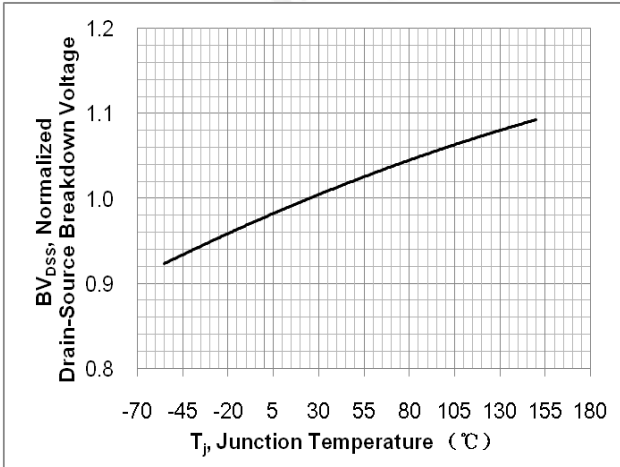


Fig. 6. On-resistance variation vs. junction temperature

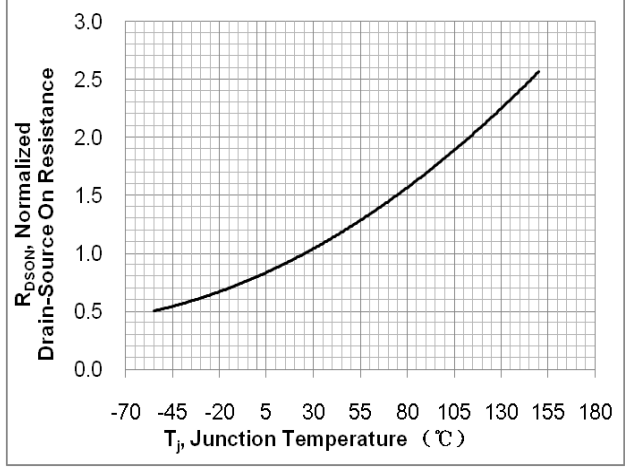


Fig. 7. Gate charge characteristics

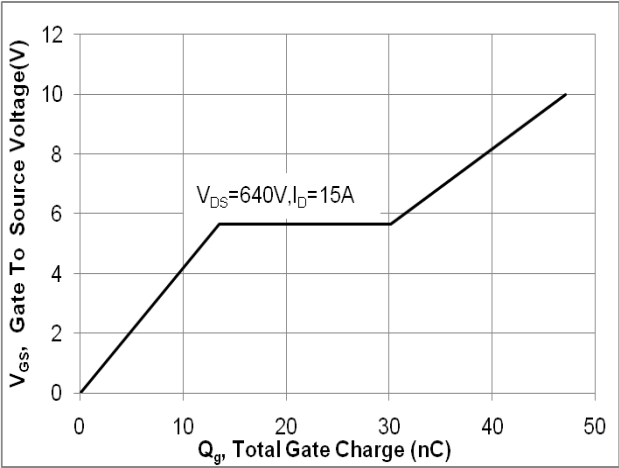


Fig. 8. Capacitance Characteristics

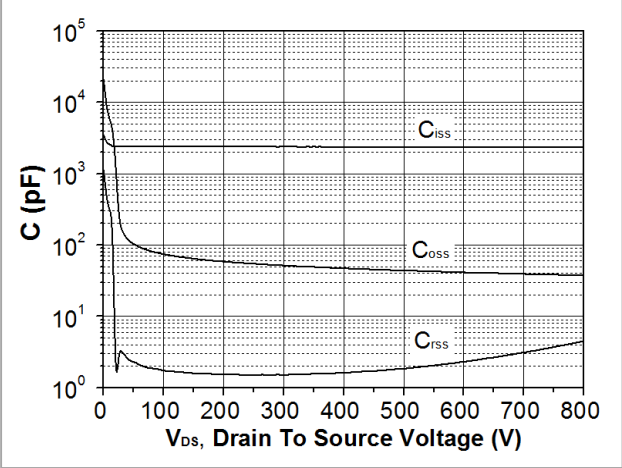


Fig. 9. Maximum safe operating area

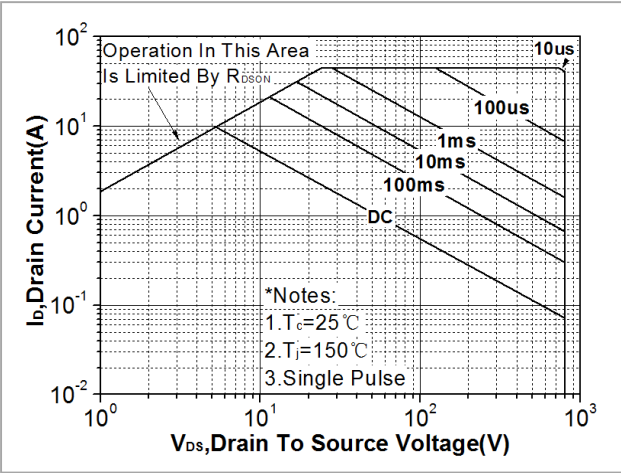


Fig. 10. Transient thermal response curve

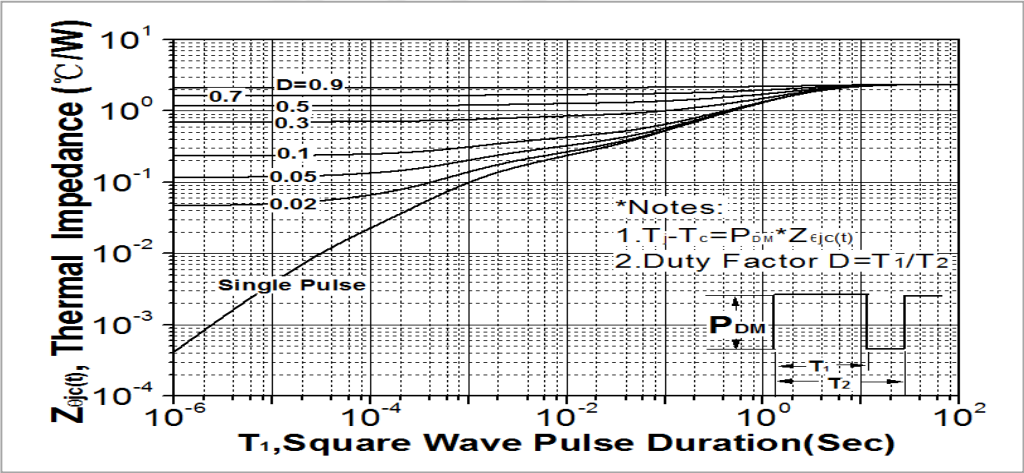


Fig. 11. Gate charge test circuit & waveform

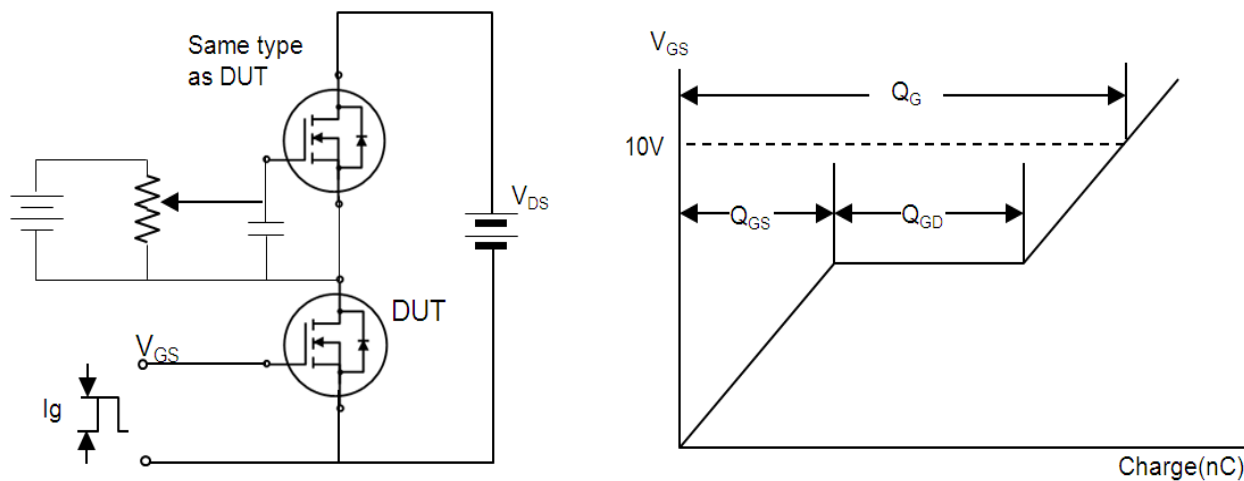


Fig. 12. Switching time test circuit & waveform

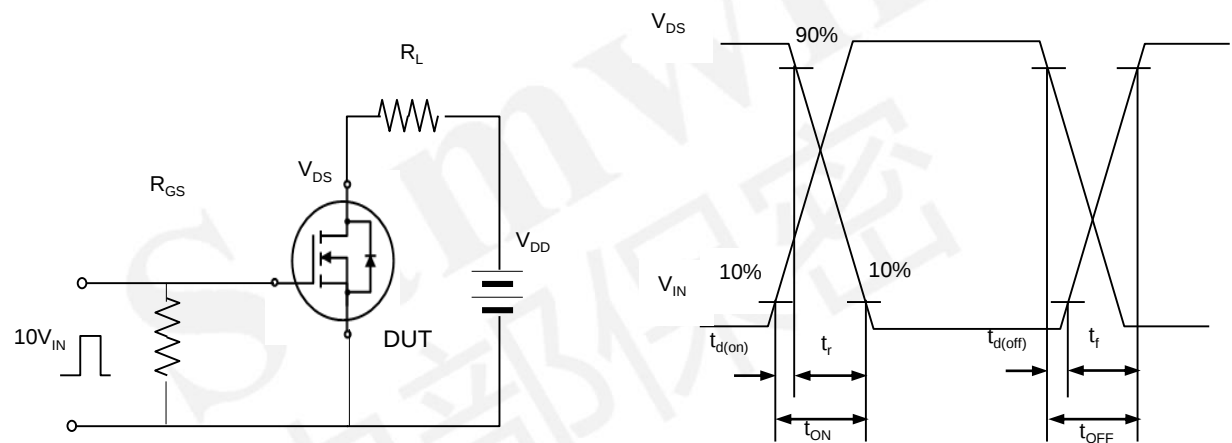


Fig. 13. Unclamped Inductive switching test circuit & waveform

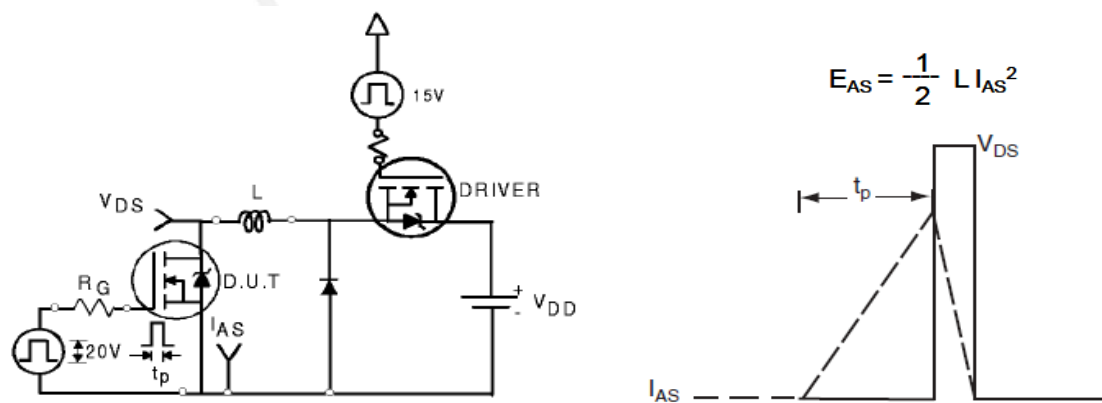
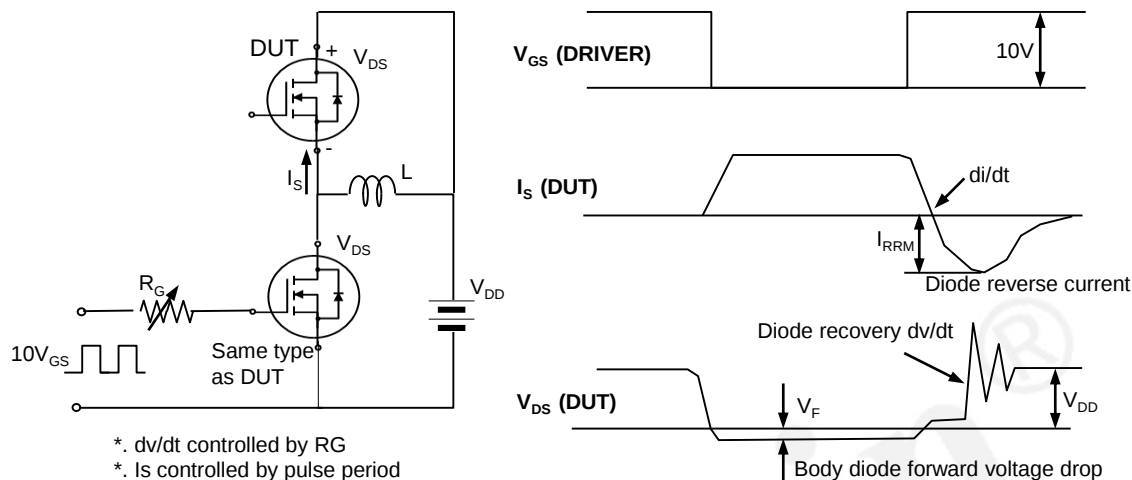


Fig. 14. Peak diode recovery dv/dt test circuit & waveform



DISCLAIMER

- * All the data & curve in this document was tested in SEMIPOWER TESTING & APPLICATION CENTER.
- * This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.
- * Qualification standards can also be found on the Web site (<http://www.semipower.com.cn>) 
- * Suggestions for improvement are appreciated, Please send your suggestions to samwin@samwinsemi.com